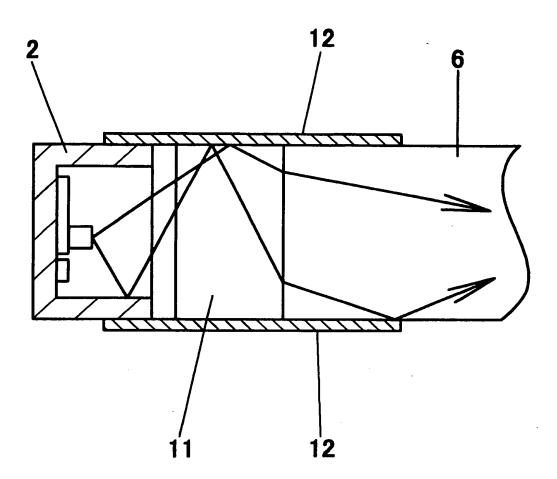
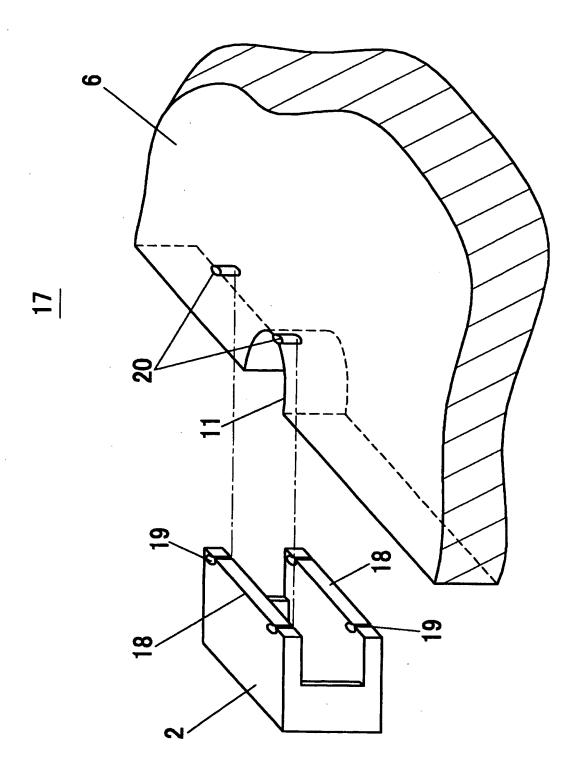
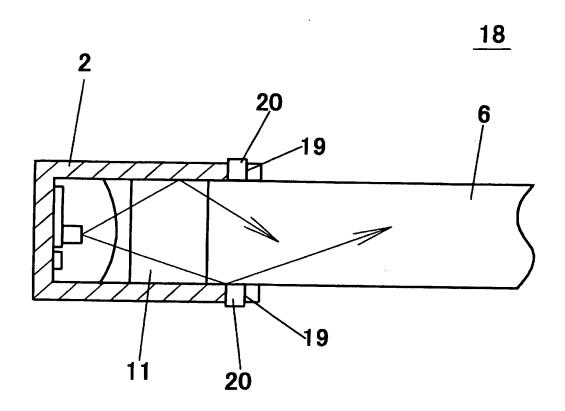
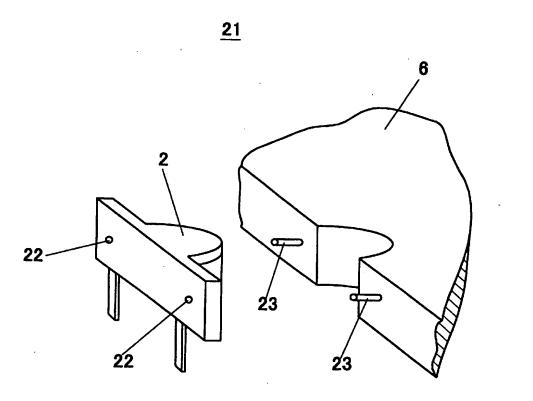


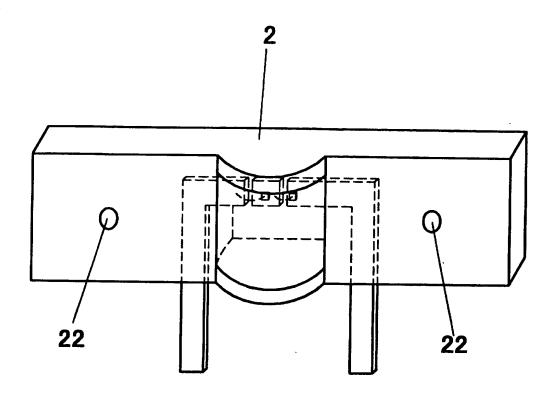
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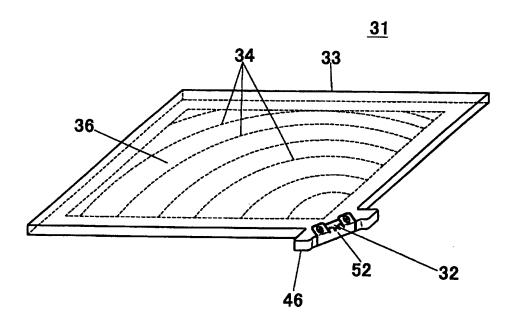


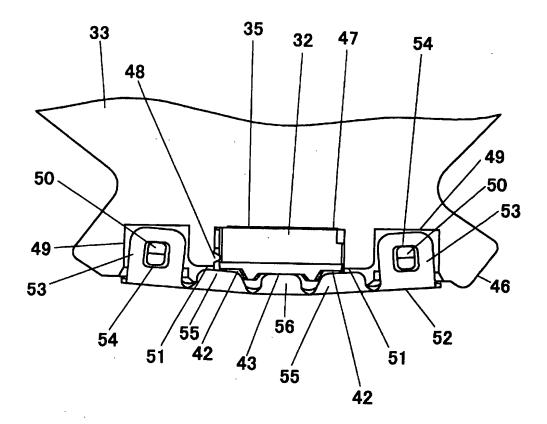




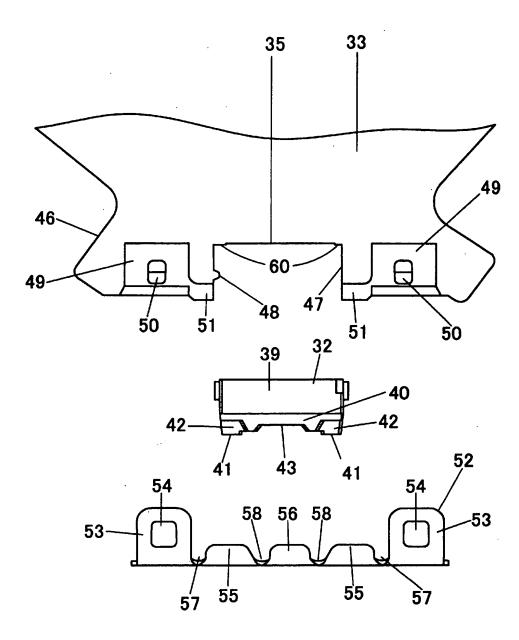


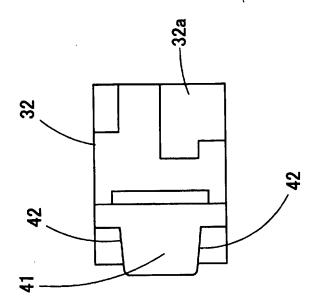


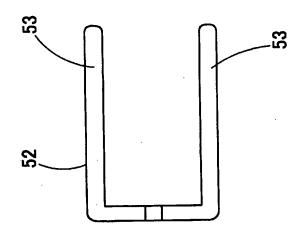


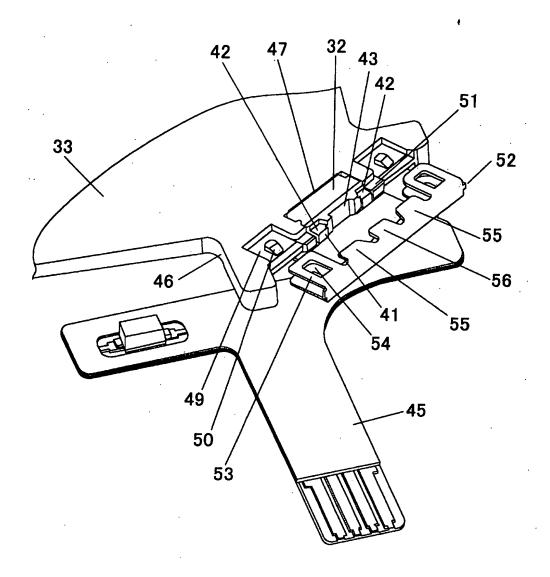


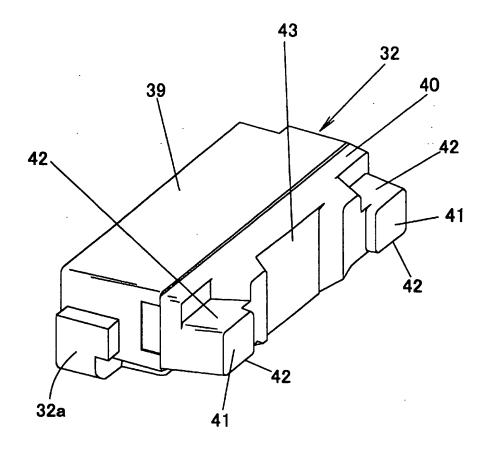
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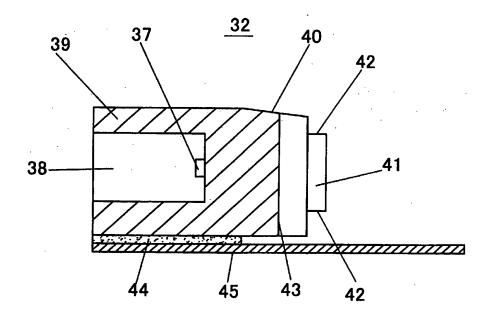


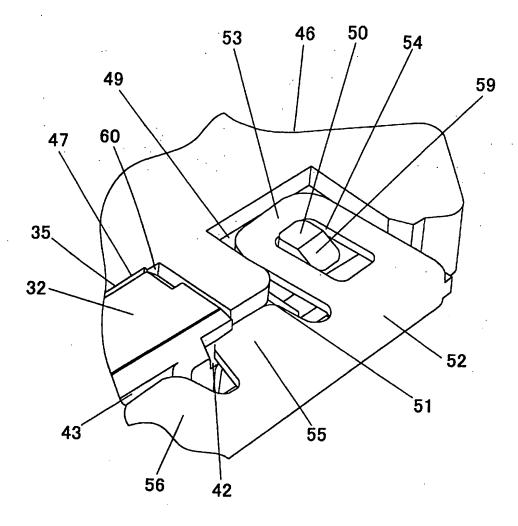


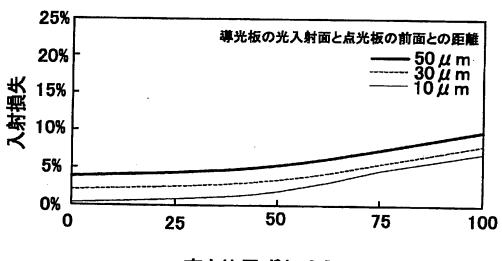




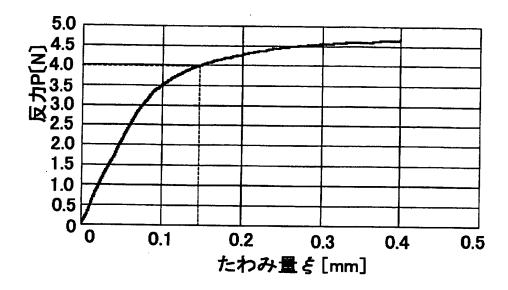


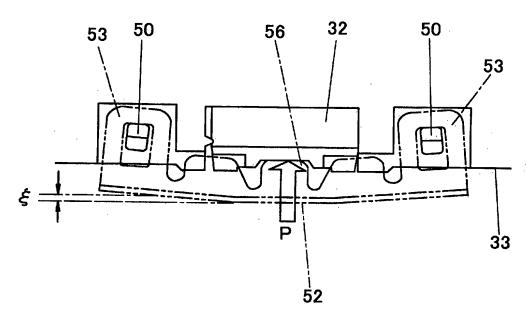


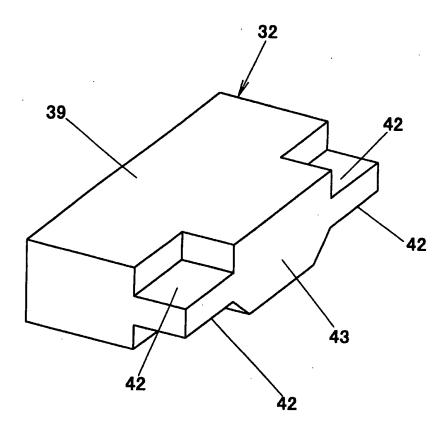


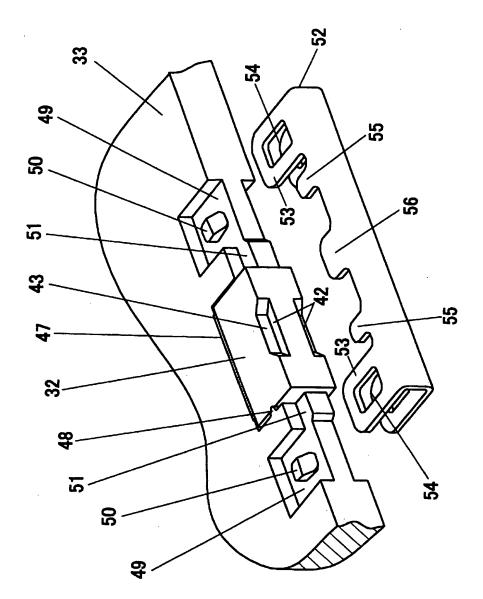


高さ位置ずれδ[μm]



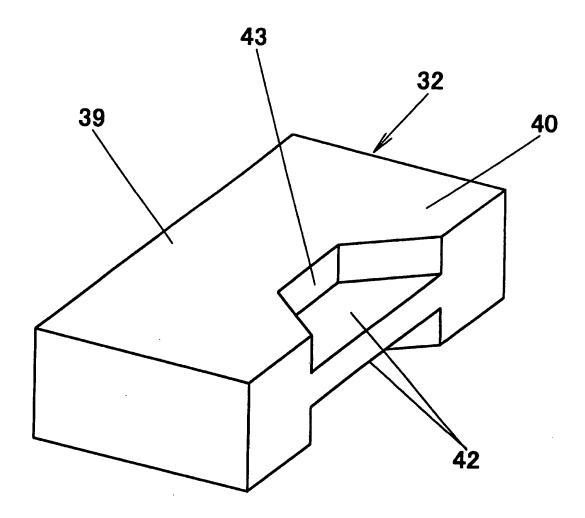


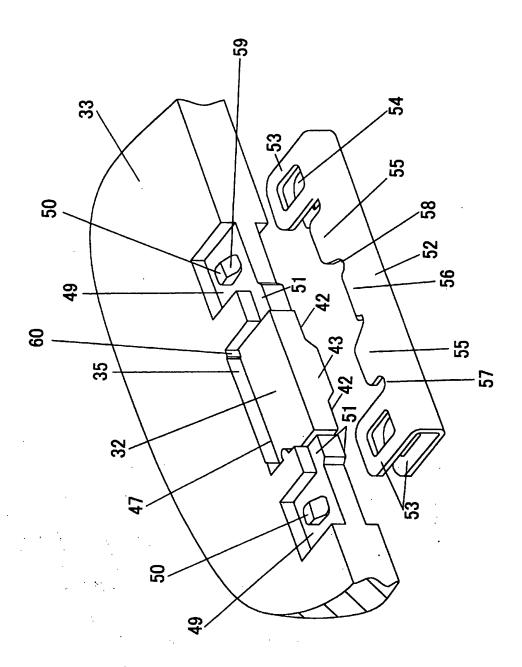


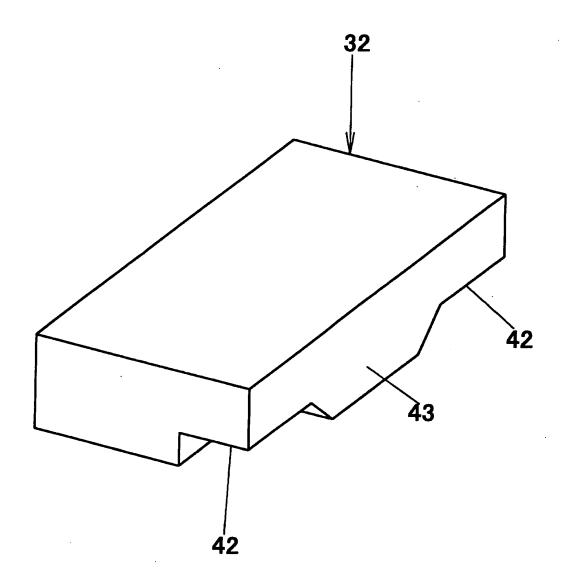


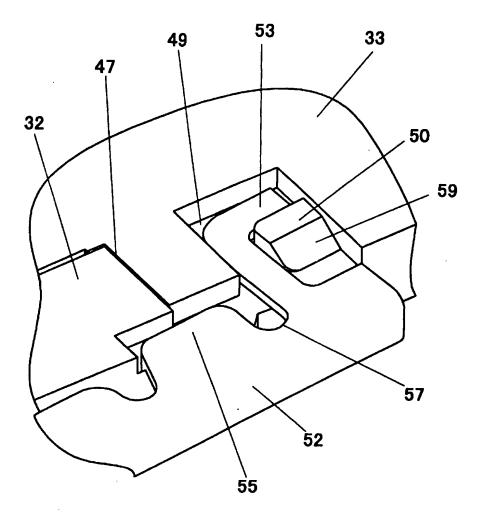
17/29

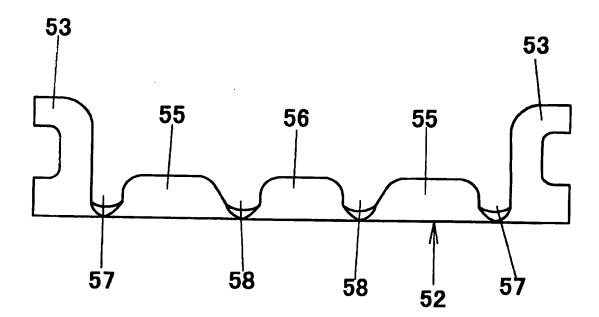
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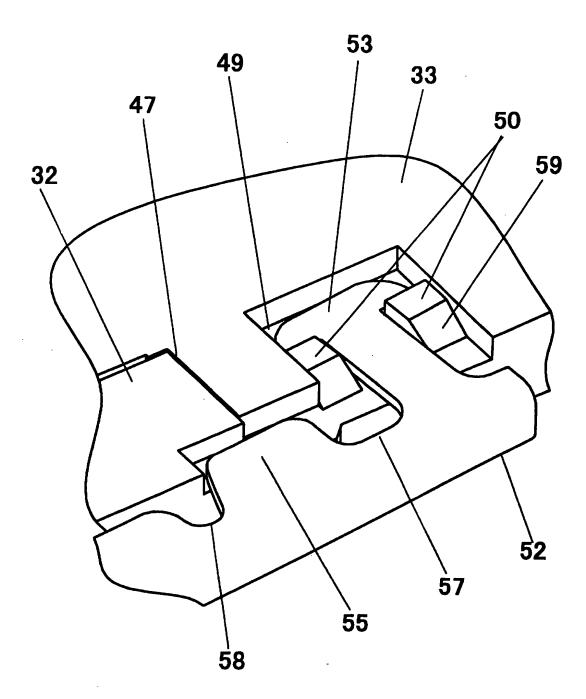


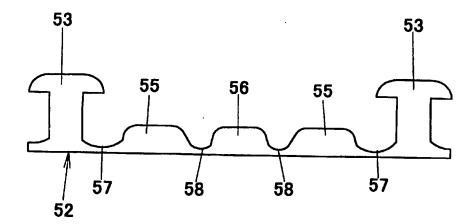


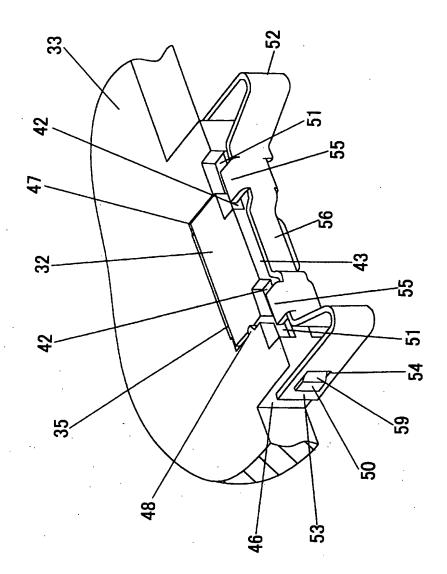


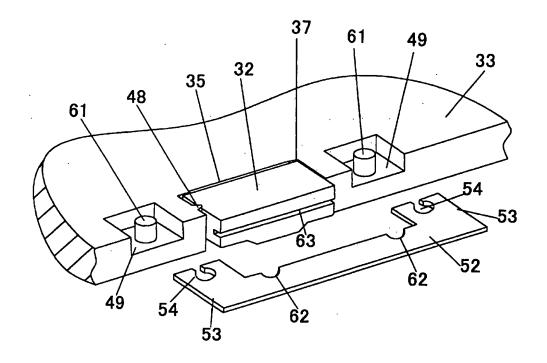


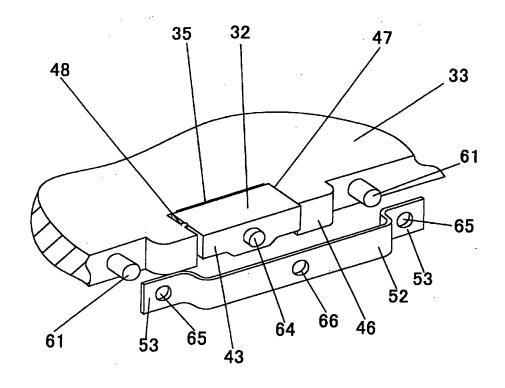


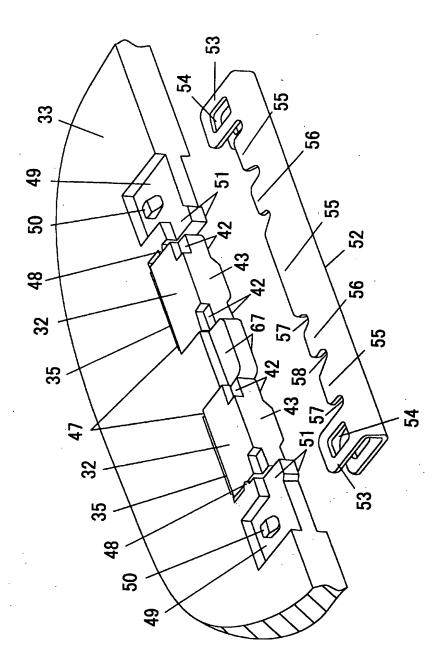


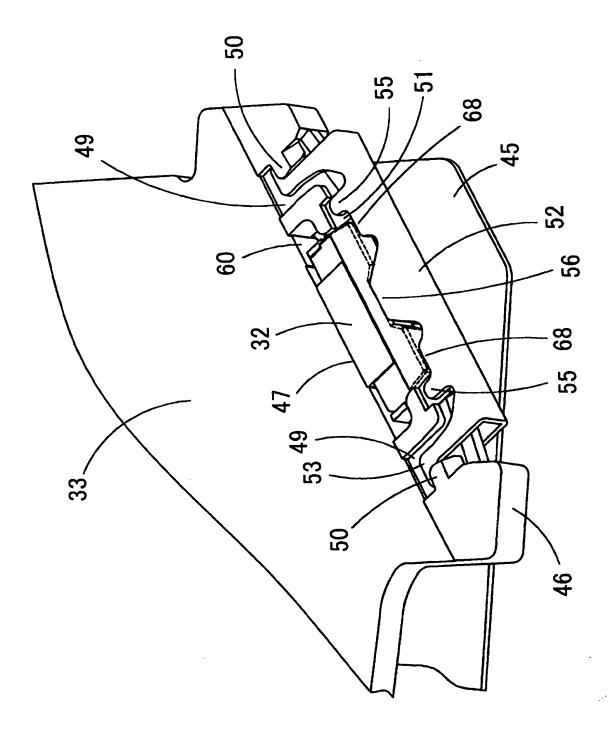


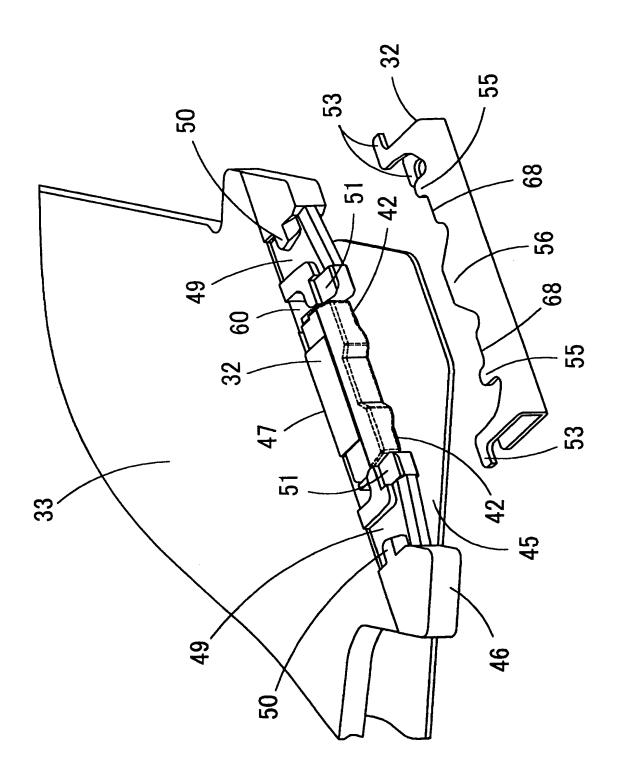












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